

FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT		ATTY. DOCKET NO. 1875.2590001 FIRST NAMED INVENTOR Akira ITO FILING DATE Herewith on February 9, 2004		APPLICATION NO. To Be Assigned 10/773263 ART UNIT To Be Assigned 2813			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>QMB</i>	AA1	5,306,656	04/26/1994	Williams et al.			
<i>QMB</i>	AB1	5,774,011	06/30/1998	Au et al.			
<i>QMB</i>	AC1	6,525,955	02/25/2003	Smith et al.			
<i>QMB</i>	AD1	20020074616	06/20/2002	Chen et al.			
<i>QMB</i>	AE1	20030123314	07/03/2003	Buer et al.			
<i>QMB</i>	AF1	20030128576	07/10/2003	Smith et al.			
<i>QMB</i>	AG1	20010050407 A1	12/2001	Gelsomini et al.			
<i>QMB</i>	AH1	6,388,305 B1	05/2002	Bertin et al.			
<i>QMB</i>	AI1	5,163,180	11/1992	Etoukhy et al.			
<i>QMB</i>	AJ1	6,515,931	02/2003	Marr et al.			
<i>QMB</i>	AK1	6,326,651	12/2001	Manabe, Yoshio			
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
<i>QMB</i>	AL1	0 495 317 A1	07/1992	EP			Yes
	AM1						No
	AN1						Yes
	AO1						No
	AP1						Yes
OTHER (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>QMB</i>	AR	1	Copy of European Search Report from EP Appl. No. 03016223.4, 4 pages (dated November 20, 2003).				
<i>QMB</i>	AS	1	B. Kaczer et al., "Consistent Model for Short-Channel nMOSFET Post-Hard-Breakdown Characteristics," 2001 Symposium on VLSI Technology Digest of Technical Papers, pp. 121-122, 2001.				
<i>QMB</i>	AT	1	R. Degraeve et al., "Relation Between Breakdown Mode and Location in Short-Channel nMOSFETs and its impact on Reliability Specifications," IEEE, 7 pages 2001.				
EXAMINER <i>George M. Mc</i>				DATE CONSIDERED <i>6/24/04</i>			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>QMB</i>	AA2	6,266,269	07/2001	Karp et al.			
<i>QMB</i>	AB2	6,545,928	04/2003	Ooishi et al.			
<i>QMB</i>	AC2	6,518,614	02/2003	Breitwisch et al.			
<i>QMB</i>	AD2	5,946,575	08/1999	Yamaoka et al.			
	AE2						
	AF2						
	AG2						
	AH2						
	AI2						
	AJ2						
	AK2						

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
/	AL2	/		/			Yes
						No	
	AM2					Yes	
						No	
	AN2					Yes	
							N
	AO2						Y s
							No
	AP2						Yes
							N

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
/	AR	2	/
	AS	2	
	AT	2	

EXAMINER *Quinn M. Dotson* **6/24/04**

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